

**Features**

- Low Voltage and Standard Voltage Operation
  - 5.0 V (V<sub>CC</sub> = 4.5 V to 5.5 V)
  - 3.0 V (V<sub>CC</sub> = 2.7 V to 5.5 V)
- User Selectable Internal Organization
  - 1K: 128 x 8 or 64 x 16
  - 2K: 256 x 8 or 128 x 16
  - 4K: 512 x 8 or 256 x 16
- Three-Wire Serial Interface
- Self-Timed Write Cycle (10 ms Max)
- High Reliability
  - Endurance: 100,000 Cycles
  - Data Retention: 100 Years
- 8-Pin PDIP, JEDEC SOIC, and EIAJ SOIC Packages

**Description**

The AT93C46/56/66 provides 1024/2048/4096 bits of serial E<sup>2</sup>PROM (Electrically Erasable Programmable Read Only Memory) organized as 64/128/256 words of 16 bits each, when the ORG Pin is connected to V<sub>CC</sub> and 128/256/512 words of 8 bits each when it is tied to ground. The device is optimized for use in many industrial and commercial applications where low power and low voltage operation are essential. The AT93C46/56/66 is available in space saving 8-pin PDIP and 8-pin JEDEC and EIAJ SOIC packages.

The AT93C46/56/66 is enabled through the Chip Select pin (CS), and accessed via a 3-wire serial interface consisting of Data Input (DI), Data Output (DO), and Shift Clock (SK). Upon receiving a READ instruction at DI, the address is decoded and the data is clocked out serially on the data output pin DO. The WRITE cycle is completely self-timed and no separate ERASE cycle is required before WRITE. The WRITE cycle is only enabled when the part is in the ERASE/WRITE ENABLE state. When CS is brought "high" following the initiation of a WRITE cycle, the DO pin outputs the READY/BUSY status of the part.

Atmel's E<sup>2</sup>PROMs are designed and tested for applications requiring extended endurance. Devices in this family are guaranteed for 100,000 ERASE/WRITE cycles and 100-year data retention. The AT93C46/56/66 is available in 5.0 V ± 10% and 2.7 V to 5.5 V versions.

**3-Wire  
Serial CMOS  
E<sup>2</sup>PROMs**

1K (128 x 8 or 64 x 16)

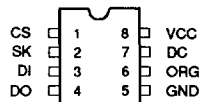
2K (256 x 8 or 128 x 16)

4K (512 x 8 or 256 x 16)

**Preliminary**

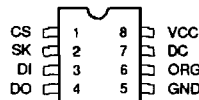
**Pin Configurations**

Pin Name	Function
CS	Chip Select
SK	Serial Data Clock
DI	Serial Data Input
DO	Serial Data Output
GND	Ground
V <sub>CC</sub>	Power Supply
ORG	Internal Organization
DC	Don't Connect

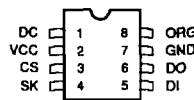


8-Pin PDIP

Rotated (R)  
(1K JEDEC Only)



8-Pin SOIC



8-Pin SOIC

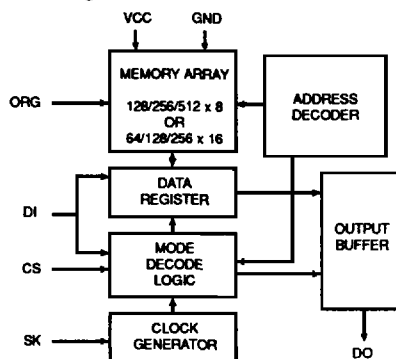


## Absolute Maximum Ratings\*

Operating Temperature.....	-55°C to +125°C
Storage Temperature.....	-65°C to +150°C
Voltage on Any Pin with Respect to Ground.....	-1.0 V to +7.0 V
Maximum Operating Voltage.....	6.25 V
DC Output Current.....	5.0 mA

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## Block Diagram <sup>(1)</sup>



Note:

1. When the ORG pin is connected to V<sub>CC</sub>, the x 16 organization is selected. When it is connected to ground, the x 8 organization is selected. If the ORG pin is left unconnected, then an internal pullup device will select the x 16 organization.

## D.C. Characteristics

Applicable over recommended operating range from: T<sub>AI</sub> = -40°C to +85°C, V<sub>CC</sub> = +2.7 V to +5.5 V, T<sub>AC</sub> = 0°C to +70°C, V<sub>CC</sub> = +2.7 V to +5.5 V (unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Max	Units
I <sub>CC1</sub>	Operating Current CMOS Input Levels	CS = V <sub>IH</sub> , SK = 1.0 MHz <sup>(1)</sup> SK = 0.5 MHz <sup>(1)</sup>		2	mA
I <sub>CC2</sub>	Operating Current TTL Input Levels	CS = V <sub>IH</sub> , SK = 1.0 MHz <sup>(1)</sup> SK = 0.5 MHz <sup>(1)</sup>		3	mA
I <sub>CC3</sub>	Standby Current	CS = 0 V, SK = 1.0 MHz <sup>(1)</sup> SK = 0.5 MHz <sup>(1)</sup>		100	μA
I <sub>IL</sub>	Input Leakage	V <sub>IN</sub> = 0 V to V <sub>CC</sub>	-2.5 -10	2.5 10	μA
I <sub>OL</sub>	Output Leakage	V <sub>IN</sub> = 0 V to V <sub>CC</sub>	-2.5 -10	2.5 10	μA
V <sub>IL1</sub> V <sub>IH1</sub>	Input Low Voltage Input High Voltage	4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V	2	0.8	V
V <sub>IL2</sub> V <sub>IH2</sub>	Input Low Voltage Input High Voltage	2.7 V ≤ V <sub>CC</sub> ≤ 5.5 V	-0.1 2	0.6 V <sub>CC</sub> + 1	V
V <sub>OL1</sub> V <sub>OH1</sub>	Output Low Voltage Output High Voltage	4.5 V ≤ V <sub>CC</sub> ≤ 5.5 V I <sub>OL</sub> = 2.1 mA I <sub>OH</sub> = -400 μA	2.4	0.4	V V
V <sub>OL2</sub> V <sub>OH2</sub>	Output Low Voltage Output High Voltage	2.7 V ≤ V <sub>CC</sub> ≤ 5.5 V I <sub>OL</sub> = 10 μA I <sub>OH</sub> = -10 μA	V <sub>CC</sub> - 0.2	0.2	V V

Note: 1. Devices operate at 1.0 MHz at V<sub>CC</sub> = 5.0 V ± 10% at commercial temperature. All low voltage and industrial parts operate at 0.5 MHz.

**A.C. Characteristics**

Applicable over recommended operating range from  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = +2.7\text{ V}$  to  $+5.5\text{ V}$ ,  $CL = 1\text{ TTL Gate}$  and  $100\text{ pF}$  (unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Max	Units
f <sub>SK</sub>	SK Clock Frequency		0 0	1 0.5	MHz
t <sub>SKH</sub>	SK High Time	Note 1 Note 2	500 500		ns
t <sub>SKL</sub>	SK Low Time	Note 1 Note 2	250 500		ns
t <sub>CS</sub>	Minimum CS Low Time	Note 3 Note 4	250 500		ns
t <sub>CSS</sub>	CS Setup Time	Relative to SK	50 100		ns
t <sub>DIS</sub>	DI Setup Time	Relative to SK	100 200		ns
t <sub>CSH</sub>	CS Hold Time	Relative to SK	0		ns
t <sub>DIH</sub>	DI Hold Time	Relative to SK	100 200		ns
t <sub>PD1</sub>	Output Delay to '1'	AC Test		500 1000	ns
t <sub>PD0</sub>	Output Delay to '0'	AC Test		500 1000	ns
t <sub>SV</sub>	CS to Status Valid	AC Test		500 1000	ns
t <sub>DF</sub>	CS to DO in High Impedance	AC Test CS = V <sub>IL</sub>		100 200	ns
t <sub>WP</sub>	Write Cycle Time			10	ms
	Endurance	Number of Data Changes per Bit	Typical 100,000		Cycles

Notes:

- The SK frequency specification for Commercial parts specifies a minimum SK clock period of 1  $\mu\text{s}$ , therefore in an SK clock cycle  $t_{SKH} + t_{SKL}$  must be greater than or equal to 1  $\mu\text{s}$ . For example if  $t_{SKL} = 250\text{ ns}$  then the minimum  $t_{SKH} = 750\text{ ns}$  in order to meet the SK frequency specification.
- The SK frequency specification for extended Temperature parts specifies a minimum SK clock period of 2  $\mu\text{s}$ , therefore in an SK clock cycle  $t_{SKH} + t_{SKL}$  must be greater than or equal to 2  $\mu\text{s}$ . For example, if the  $t_{SKL} = 500\text{ ns}$  then the minimum  $t_{SKH} = 1.5\text{ }\mu\text{s}$  in order to meet the SK frequency specification.
- For Commercial parts CS must be brought low for a minimum of 250 ns ( $t_{CS}$ ) between consecutive instruction cycles.
- For Extended Temperature parts CS must be brought low for a minimum of 500 ns ( $t_{CS}$ ) between consecutive instruction cycles.

**Pin Capacitance <sup>(1)</sup>**

Applicable over recommended operating range from  $T_A = 25^{\circ}\text{C}$ ,  $f = 1.0\text{ MHz}$ ,  $V_{CC} = +5.0\text{ V}$  (unless otherwise noted)

	Test Conditions	Max	Units	Conditions
C <sub>OUT</sub>	Output Capacitance (DO)	5	pF	V <sub>OUT</sub> = 0 V
C <sub>IN</sub>	Input Capacitance (CS, SK, DI)	5	pF	V <sub>IN</sub> = 0 V

Note: 1. This parameter is characterized and is not 100% tested.



## Functional Description

The AT93C46/56/66 is accessed via a simple and versatile 3-wire serial communication interface. Device operation is controlled by 7 instructions issued by the host processor. A valid instruction consists of a Start Bit (logic '1') followed by the appropriate Op Code and the desired memory Address location.

**READ (READ):** The Read (READ) instruction contains the Address code for the memory location to be read. After the instruction and address are decoded, data from the selected memory location is available at the serial output pin DO. Output data changes are synchronized with the rising edges of serial clock SK. It should be noted that a dummy bit (logic '0') precedes the 8- or 16-bit data output string.

**ERASE/WRITE (EWEN):** To assure data integrity, the part automatically goes into the Erase/Write Disable (EWDS) state when power is first applied. An Erase/Write Enable (EWEN) instruction must be executed first before any programming instructions can be carried out. Please note that once in the Erase/Write Enable state, programming remains enabled until an Erase/Write Disable (EWDS) instruction is executed or VCC power is removed from the part.

**ERASE (ERASE):** The Erase (ERASE) instruction programs all bits in the specified memory location to the logical '1' state. The self-timed erase cycle starts once the ERASE instruction and address are decoded. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). A logic '0' at pin DO indicates that the selected memory location has been erased, and the part is ready for another instruction.

**WRITE (WRITE):** The Write (WRITE) instruction contains the 8 or 16 bits of data to be written into the specified memory location. The self-timed programming cycle starts after the last bit of data is received at serial data input pin DI. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). A logic '0' at DO indicates that programming is still in progress. A logic '1' indicates that the memory location at the specified address has been written with the data pattern contained in the instruction and the part is ready for further instructions.

**ERASE ALL (ERAL):** The Erase All (ERAL) instruction programs every bit in the memory array to the logic '1' state and is primarily used for testing purposes. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). The ERAL instruction is valid only at  $V_{CC} = 5.0 V \pm 10\%$ .

**WRITE ALL (WRAL):** The Write All (WRAL) instruction programs all memory locations with the data patterns specified in the instruction. The DO pin outputs the READY/BUSY status of the part if CS is brought high after being kept low for a minimum of 250 ns ( $t_{CS}$ ). The WRAL instruction is valid only at  $V_{CC} = 5.0 V \pm 10\%$ .

**ERASE/WRITE DISABLE (EWDS):** To protect against accidental data disturb, the Erase/Write Disable (EWDS) instruction disables all programming modes and should be executed after all programming operations. The operation of the READ instruction is independent of both the EWEN and EWDS instructions and can be executed at any time.

## Instruction Set for the AT93C46

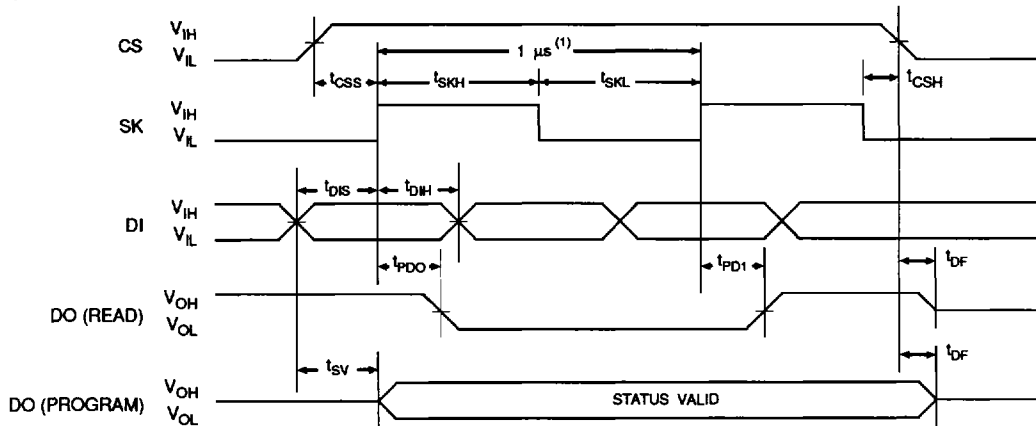
Instruction	SB	Op Code	Address		Data		Comments
			x 8	x 16	x 8	x 16	
READ	1	10	A <sub>6</sub> -A <sub>0</sub>	A <sub>5</sub> -A <sub>0</sub>			Reads data stored in memory, at specified address.
EWEN	1	00	11XXXXX	11XXXX			Write enable must precede all programming modes.
ERASE	1	11	A <sub>6</sub> -A <sub>0</sub>	A <sub>5</sub> -A <sub>0</sub>			Erase memory location A <sub>n</sub> - A <sub>0</sub> .
WRITE	1	01	A <sub>6</sub> -A <sub>0</sub>	A <sub>5</sub> -A <sub>0</sub>	D <sub>7</sub> -D <sub>0</sub>	D <sub>15</sub> -D <sub>0</sub>	Writes memory location A <sub>n</sub> - A <sub>0</sub> .
ERAL	1	00	10XXXXX	10XXXX			Erases all memory locations. Valid only at $V_{CC} = 4.5 V$ to $5.5 V$ .
WRAL	1	00	01XXXXX	01XXXX	D <sub>7</sub> -D <sub>0</sub>	D <sub>15</sub> -D <sub>0</sub>	Writes all memory locations. Valid only at $V_{CC} = 4.5 V$ to $5.5 V$ .
EWDS	1	00	00XXXXX	00XXXX			Disables all programming instructions.

Instruction Set for the AT93C56 and AT93C66

Instruction	SB	Op Code	Address		Data		Comments
			x 8	x 16	x 8	x 16	
READ	1	10	A <sub>8</sub> -A <sub>0</sub>	A <sub>7</sub> -A <sub>0</sub>			Reads data stored in memory, at specified address.
EWEN	1	00	11XXXXXXXX	11XXXXXXXX			Write enable must precede all programming modes.
ERASE	1	11	A <sub>8</sub> -A <sub>0</sub>	A <sub>7</sub> -A <sub>0</sub>			Erases memory location A <sub>n</sub> - A <sub>0</sub> .
WRITE	1	01	A <sub>8</sub> -A <sub>0</sub>	A <sub>7</sub> -A <sub>0</sub>	D <sub>7</sub> -D <sub>0</sub>	D <sub>15</sub> -D <sub>0</sub>	Writes memory location A <sub>n</sub> - A <sub>0</sub> .
ERAL	1	00	10XXXXXXXX	10XXXXXXXX			Erases all memory locations. Valid only at V <sub>CC</sub> = 4.5 V to 5.5 V.
WRAL	1	00	01XXXXXXXX	01XXXXXXXX	D <sub>7</sub> -D <sub>0</sub>	D <sub>15</sub> -D <sub>0</sub>	Writes all memory locations. Valid when V <sub>CC</sub> = 5.0 V ± 10% and Disable Register cleared.
EWDS	1	00	00XXXXXXXX	00XXXXXXXX			Disables all programming instructions.

Timing Diagrams

Synchronous Data Timing



Note: 1. This is the minimum SK period.

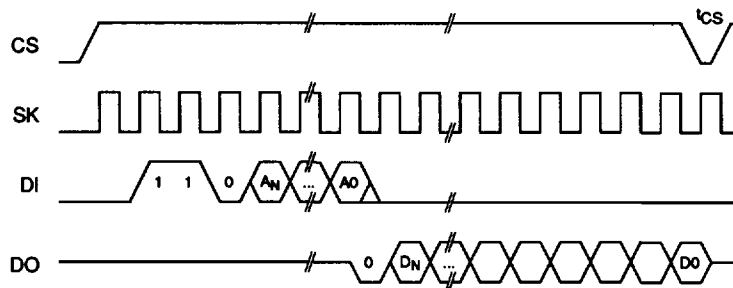
Organization Key for Timing Diagrams

I/O	Density 1K		Density 2K		Density 4K	
	x 8	x 16	x 8	x 16	x 8	x 16
A <sub>N</sub>	A <sub>6</sub>	A <sub>5</sub>	A <sub>8</sub>	A <sub>7</sub>	A <sub>8</sub>	A <sub>7</sub>
D <sub>N</sub>	D <sub>7</sub>	D <sub>15</sub>	D <sub>7</sub>	D <sub>15</sub>	D <sub>7</sub>	D <sub>15</sub>

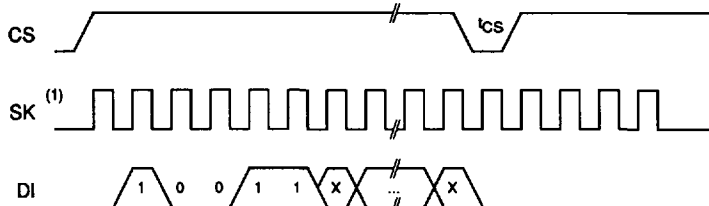


## Timing Diagrams (Continued)

### READ Timing

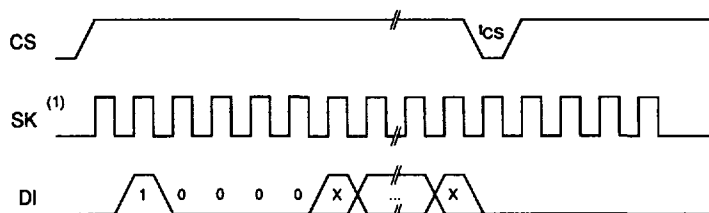


### EWEN Timing



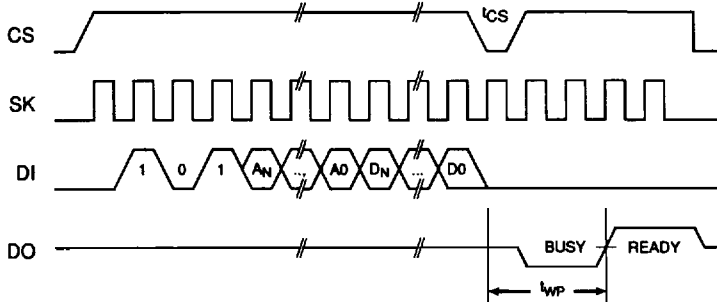
Note: 1. The AT93C56 and AT93C66 require a minimum of 11 clocks. The AT93C46 requires a minimum of 9 clock cycles.

### EWDS Timing



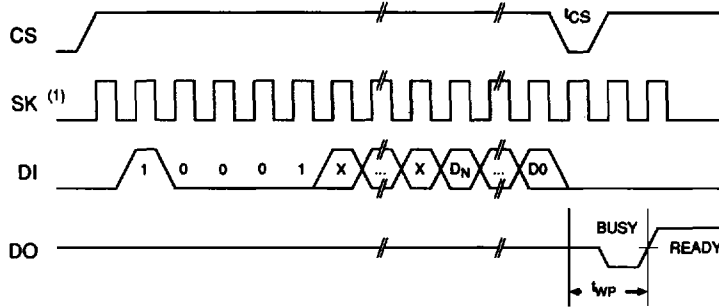
Note: 1. The AT93C56 and AT93C66 require a minimum of 11 clocks. The AT93C46 requires a minimum of 9 clock cycles.

### WRITE Timing



Timing Diagrams (Continued)

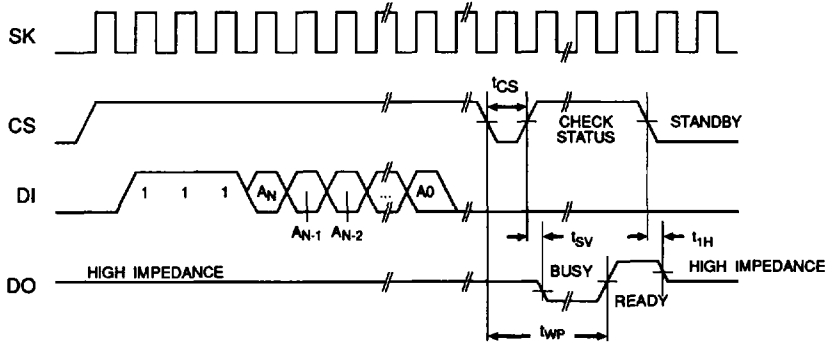
WRAL Timing <sup>(2)</sup>



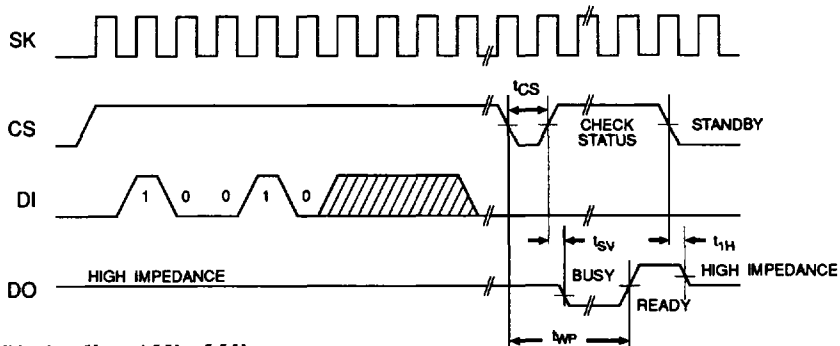
Notes: 1. The AT93C56 and AT93C66 require a minimum of 11 clocks. The AT93C46 requires a minimum of 9 clock cycles.

2. Valid only at  $V_{CC} = 4.5\text{ V to }5.5\text{ V}$ .

ERASE Timing



ERAL Timing <sup>(1)</sup>



Note: 1. Valid only at  $V_{CC} = 4.5\text{ V to }5.5\text{ V}$ .





## Ordering Information

tWP (ms)	Icc (mA)	fMAX (kHz)	Ordering Code	Package	Operation Range
10	3.0	1000	AT93C46-10PC (-2.7)	8P3	Commercial (0°C to 70°C)
			AT93C46-10SC (-2.7)	8S1	
			AT93C46R-10SC (-2.7)	8S1	
			AT93C46W-10SC (-2.7)	8S2	
			AT93C46-10PI (-2.7)	8P3	Industrial (-40°C to 85°C)
			AT93C46-10SI (-2.7)	8S1	
			AT93C46R-10SI (-2.7)	8S1	
			AT93C46W-10SI (-2.7)	8S2	
			AT93C46-10PM	8P3	Military (-55°C to 125°C)

10	3.0	1000	AT93C56-10PC (-2.7)	8P3	Commercial (0°C to 70°C)
			AT93C56-10SC (-2.7)	8S1	
			AT93C56W-10SC (-2.7)	8S2	
			AT93C56-10PI (-2.7)	8P3	Industrial (-40°C to 85°C)
			AT93C56-10SI (-2.7)	8S1	
			AT93C56W-10SI (-2.7)	8S2	
			AT93C56-10PM	8P3	Military (-55°C to 125°C)

10	3.0	1000	AT93C66-10PC (-2.7)	8P3	Commercial (0°C to 70°C)
			AT93C66-10SC (-2.7)	8S1	
			AT93C66W-10SC (-2.7)	8S2	
			AT93C66-10PI (-2.7)	8P3	Industrial (-40°C to 85°C)
			AT93C66-10SI (-2.7)	8S1	
			AT93C66W-10SI (-2.7)	8S2	
			AT93C66-10PM	8P3	Military (-55°C to 125°C)

Package Type	
<b>8P3</b>	8 Lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)
<b>8S1</b>	8 Lead, 0.150" Wide, Plastic Gull Wing Small Outline (JEDEC SOIC)
<b>8S2</b>	8 Lead, 0.200" Wide, Plastic Gull Wing Small Outline (EIAJ SOIC)
Options	
<b>Blank</b>	Standard Device (4.5 V to 5.5 V)
<b>-2.7</b>	Low Voltage (2.7 V to 5.5 V)
<b>R</b>	Rotated Pinout